

• Product Summary

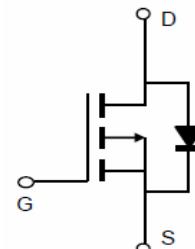
Part #	V _{DS}	R _{DS(on).typ} (@V _{GS} =10V)	R _{DS(on).typ} (@V _{GS} =4.5V)	I _D
EFM150P03M	-30V	13mΩ	18mΩ	-30A

• Description

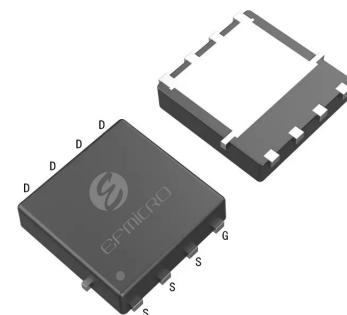
- The EFM150P03M is the high cell density trenched
- P-chMOSFETs, which provide excellent RDSON
- and gate charge for most of the synchronous buck
- converter applications.
- The EFM150P03M meet the RoHS and Green
- Product requirement, 100 % EAS guaranteed
- with full function reliability approved.

• Application

- Super Low Gate Charge 100% EAS Guaranteed
- Green Device Available Excellent CdV/dt effect decline
- Advanced high cell density Trench technology



P-Channel MOSFET



DFN3x3-8L

• Ordering Information:

Part NO.	EFM150P03M
Marking	150P03M ****
Packing Information	REEL TAPE
Basic ordering unit (pcs)	5000

• Absolute Maximum Ratings (T_C=25°C)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	-30	V
Gate-Source Voltage	V _{GS}	±20	V
Drain Current-Continuous	I _D	-30	A
Drain Current-Pulsed ^(Note 1)	I _{DM}	-120	A
Maximum Power Dissipation	P _D	15	W
Operating Junction and Storage Temperature Range	T _J , T _{STG}	-55 To 150	°C

• Thermal Characteristic

Thermal Resistance, Junction-to-Ambient ^(Note 2)	R _{θJA}	66	°C/W
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• Static Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise stated)

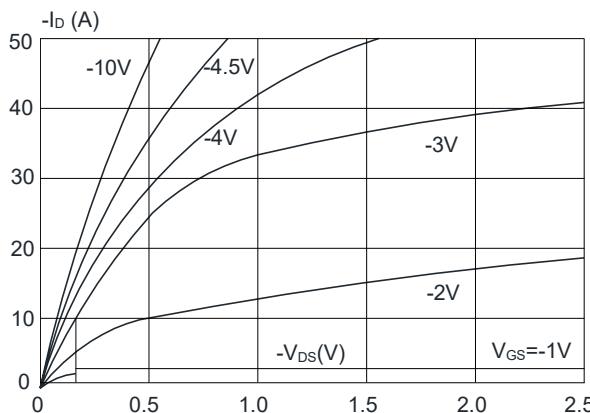
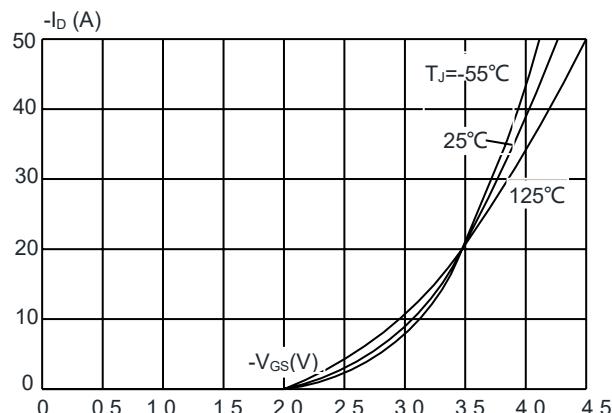
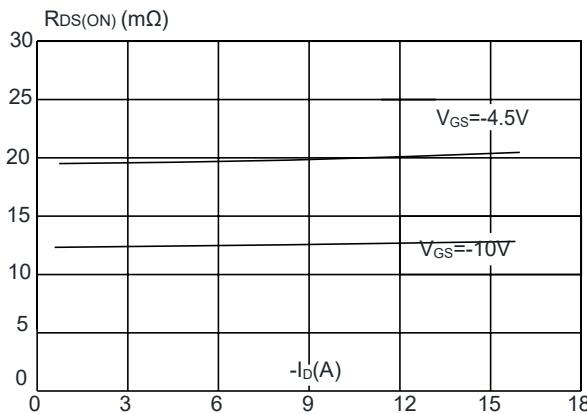
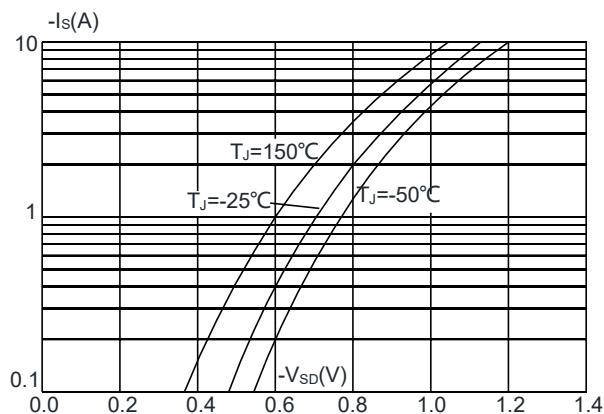
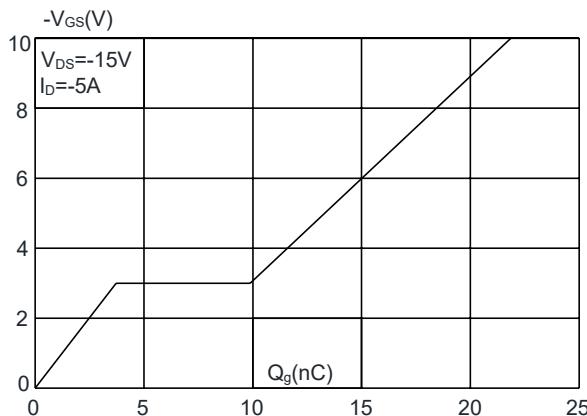
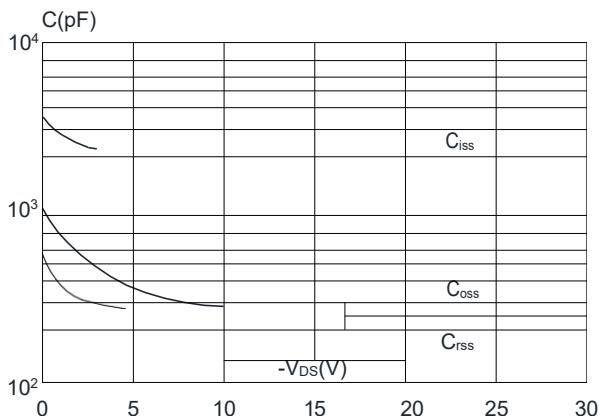
Parameter	Symbol	Condition	Min	Typ	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V} I_{\text{D}}=250\mu\text{A}$	-30	--	--	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}}=-30\text{V} V_{\text{GS}}=0\text{V}$	--	--	-1	nA
Gate-Body Leakage Current	I_{GSS}	$V_{\text{GS}}=\pm 20\text{V} V_{\text{DS}}=0\text{V}$	--	--	± 100	nA
On Characteristics <small>(Note 3)</small>						
Gate Threshold Voltage	$V_{\text{GS(th)}}$	$V_{\text{DS}}=V_{\text{GS}} I_{\text{D}}=250\mu\text{A}$	-1.0	-1.6	-2.5	V
Drain-Source On-State Resistance	$R_{\text{DS(ON)}}$	$V_{\text{GS}}=-10\text{V} I_{\text{D}}=-10\text{A}$	--	13	16	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V} I_{\text{D}}=-5\text{A}$	--	18	25	$\text{m}\Omega$
Dynamic Characteristics <small>(Note 4)</small>						
Input Capacitance	C_{iss}	$V_{\text{DS}}=-15\text{V} V_{\text{GS}}=0\text{V}$ $F=1.0\text{MHz}$	--	1330	--	PF
Output Capacitance	C_{oss}		--	183	--	PF
Reverse Transfer Capacitance	C_{rss}		--	156	--	PF
Switching Characteristics <small>(Note 4)</small>						
Turn-on Delay Time	$t_{\text{d(on)}}$	$V_{\text{DD}}=-15\text{V} I_{\text{D}}=-10\text{A}$ $V_{\text{GS}}=-10\text{V} R_{\text{G}}=2.5\Omega$	--	9	--	nS
Turn-on Rise Time	t_r		--	13	--	nS
Turn-Off Delay Time	$t_{\text{d(off)}}$		--	48	--	nS
Turn-Off Fall Time	t_f		--	20	--	nS
Total Gate Charge	Q_g	$V_{\text{DS}}=-15\text{V} I_{\text{D}}=-5\text{A}$ $V_{\text{GS}}=-10\text{V}$	--	22	--	nC
Gate-Source Charge	Q_{gs}		--	1.0	--	nC
Gate-Drain Charge	Q_{gd}		--	1.8	--	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage <small>(Note 3)</small>	V_{SD}	$V_{\text{GS}}=0\text{V} I_{\text{S}}=-15\text{A}$	--	-0.8	-1.2	V
Diode Forward Current <small>(Note 2)</small>	I_{S}		--	--	-30	A

Notes: 1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

2. EAS condition: $T_J=25^\circ\text{C}$, $V_{\text{GS}}=10\text{V}$, $R_{\text{G}}=25\Omega$, $L=0.5\text{mH}$, $I_{\text{AS}}=-12.7\text{A}$

3. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 0.5\%$

• Typical Characteristics


Figure 1: Output Characteristics

Figure 2: Typical Transfer Characteristics

Figure 3: On-resistance vs. Drain Current

Figure 4: Body Diode Characteristics

Figure 5: Gate Charge Characteristics

Figure 6: Capacitance Characteristics

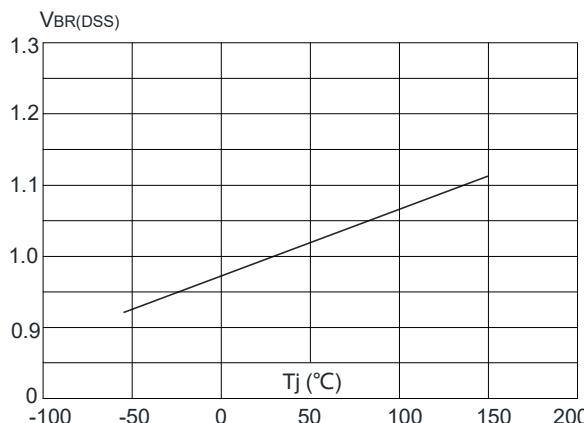


Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

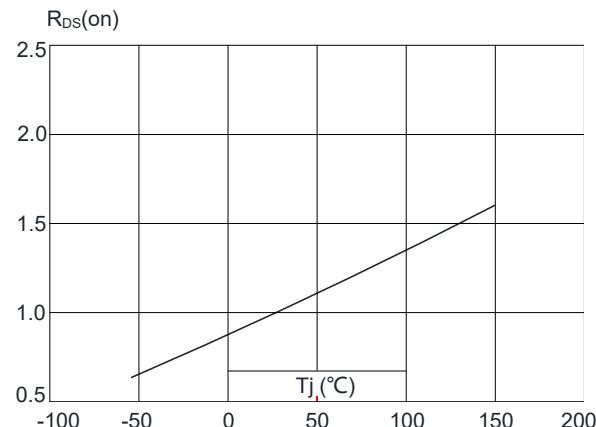


Figure 8: Normalized on Resistance vs. Junction Temperature

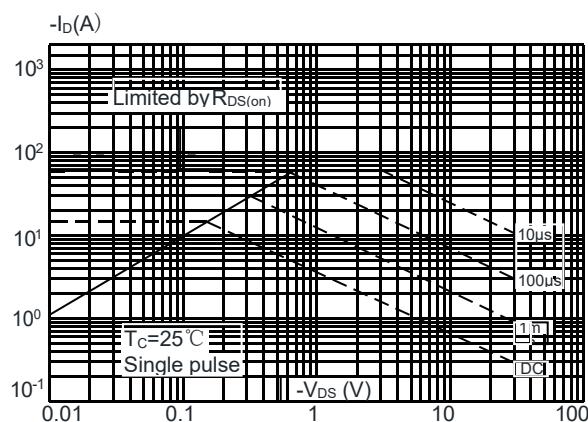


Figure 9: Maximum Safe Operating Area

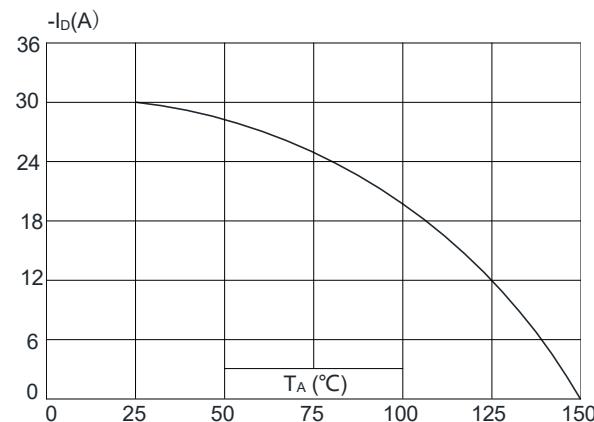


Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature

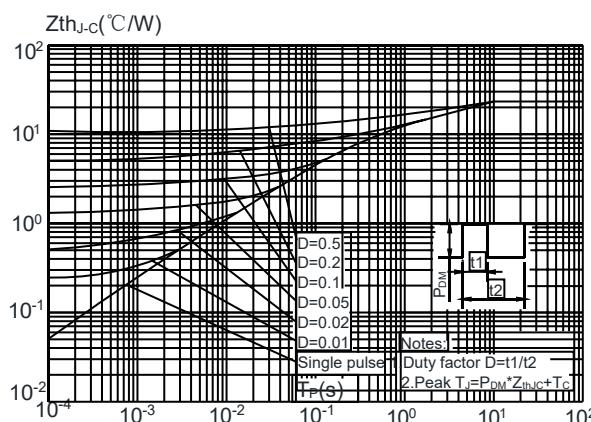
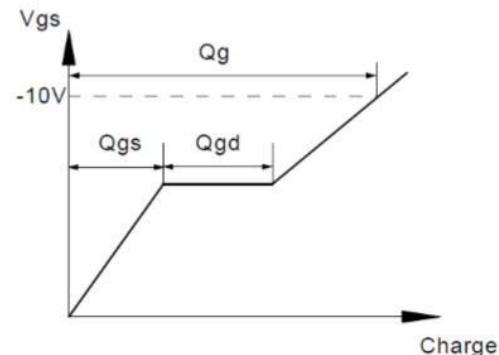
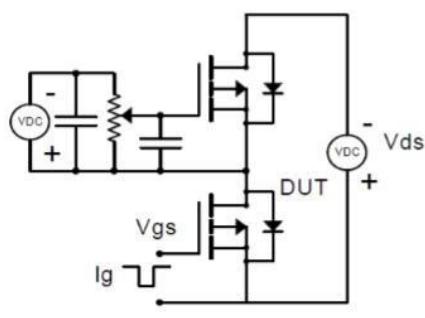


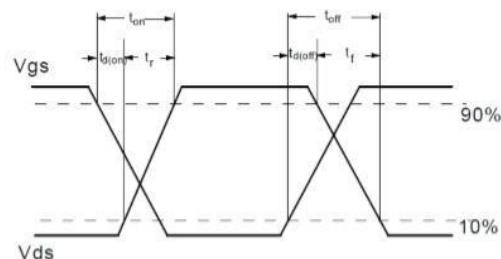
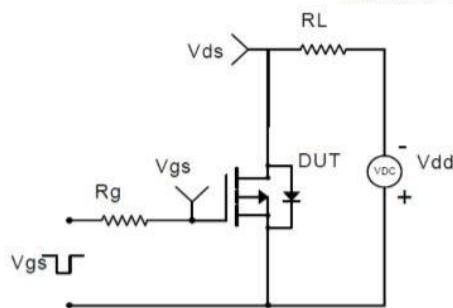
Figure 11: Maximum Effective Transient Thermal Impedance, Junction-to-Case

Test Circuit

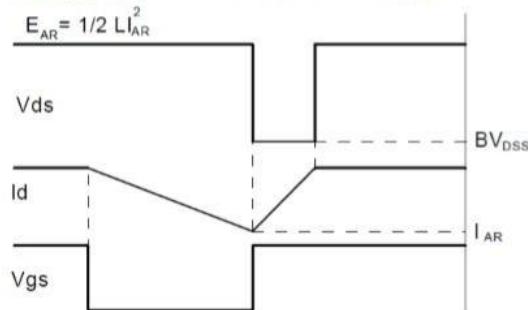
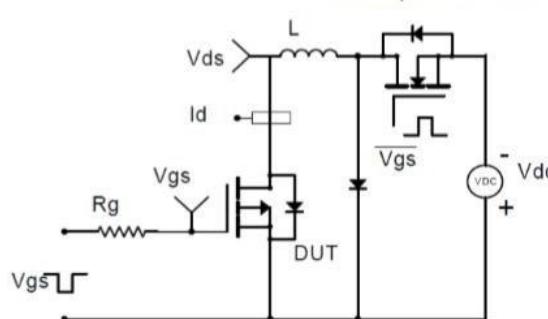
Gate Charge Test Circuit & Waveform



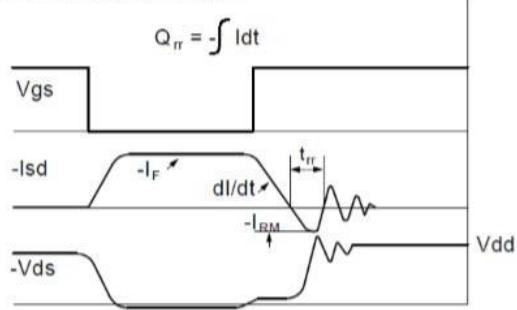
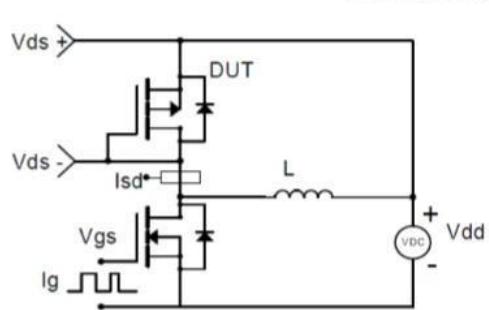
Resistive Switching Test Circuit & Waveforms

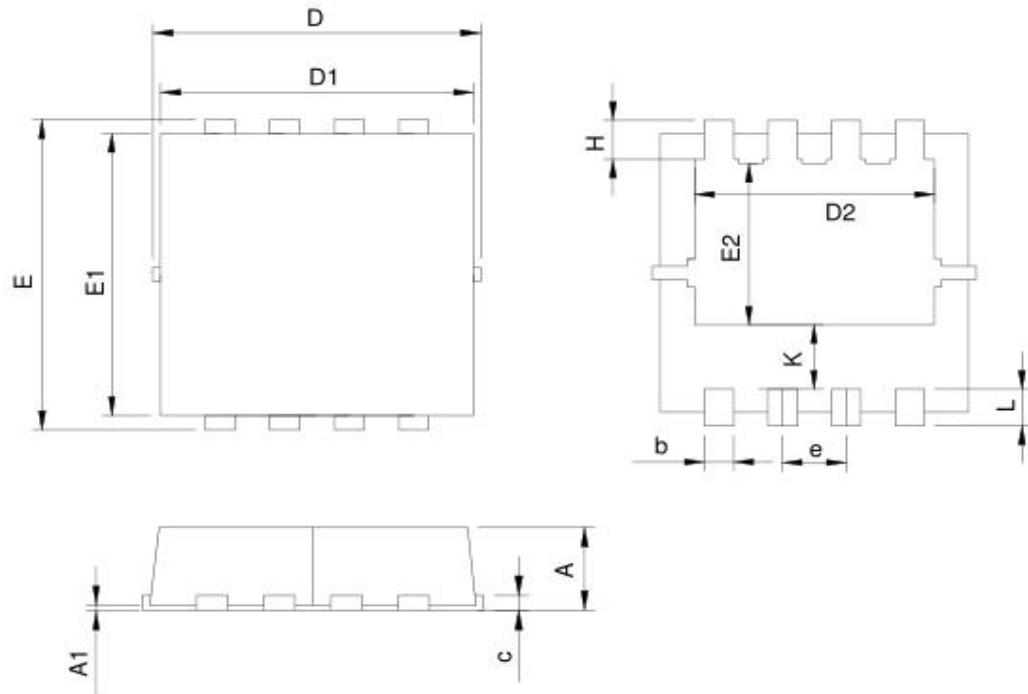


Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

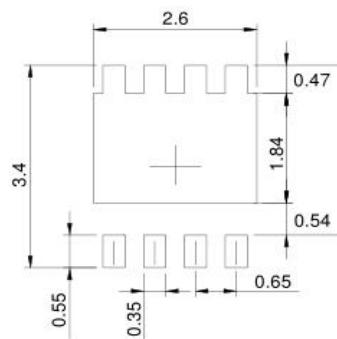


Diode Recovery Test Circuit & Waveforms



•DFN3*3 Package Outline


SYMBOL	DFN3.3x3.3-8			
	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	0.70	1.00	0.028	0.039
A1	0.00	0.05	0.000	0.002
b	0.25	0.35	0.010	0.014
c	0.14	0.20	0.006	0.008
D	3.10	3.50	0.122	0.138
D1	3.05	3.25	0.120	0.128
D2	2.35	2.55	0.093	0.100
E	3.10	3.50	0.122	0.138
E1	2.90	3.10	0.114	0.122
E2	1.64	1.84	0.065	0.072
e	0.65 BSC		0.026 BSC	
H	0.32	0.52	0.013	0.020
K	0.59	0.79	0.023	0.031
L	0.25	0.55	0.010	0.022

RECOMMENDED LAND PATTERN


UNIT: mm